### The Next Generation Solar Spectral Irradiance Monitor For the JPSS-TSIS Mission Instrument Overview and Radiometric Performance



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> Special thanks to: Steve Brown, Keith Lykke, and Allan Smith NIST & L-1 Standards and Technology, Inc.



## Solar Spectral Irradiance (SSI) Influences on Global Change

#### **Global Energy Budget Contributions**



#### **SSI Radiative Forcing Questions**

• How does the climate system respond?

- Process studies seek to quantify mechanisms by which the Earth system responds to various forcings

 ✓ Requires measurement of wavelength-dependent irradiance variability.

SSI observations will enable more realistic climate model simulations for comparisons with empirical evidence and ultimately projections of future change.

#### Measurement Goal:

"Acquire SSI time series of measurements of sufficient length, consistency, and continuity to determine climate variability and change"

Climate Data Records from Environmental Satellites: Interim Report (2004)





#### Solar Spectral Irradiance (W m<sup>-2</sup> nm<sup>-1</sup>)

Solar Spectral Irradiance is defined as the radiant power per unit area per unit wavelength interval incident on a plane surface at the top of the atmosphere that is normal to the direction from the Sun.



#### SIM Integrated Power vs. Wavelength



Total Solar Irradiance (TSI)

$$TSI_{TIM} = \int_{\lambda=0}^{\lambda=\infty} E_{\lambda} d\lambda \approx 1362 \text{ Watts/}{m^2}$$

Spectral Solar Irradiance (SSI)

$$TSI_{SIM} = \int_{\lambda=200}^{\lambda=2400} E_{\lambda} d\lambda \approx 96\%$$
 of TSI





## Short-term (Rotational) SSI Variability



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## Predicted Solar Cycle SSI Variability



NRLSSI Modeled spectral variability based on observations of UV (120-250 nm) and model of rotational modulation of plage and sunspot contrast.

Prior to SORCE SIM (2003) no continuous measurement of variability in the 400-2400 nm region





Attribute	Req't	Justification		
<b>Measurement range (Wm<sup>-2</sup>nm<sup>-1</sup>)</b> Spectral limits (0.2 - 2.4 μm)	10 <sup>-4</sup> - 10 <sup>1</sup>	Solar spectrum Full scale bounds on magnitude of SSI		
Long-term rel. stability (per year) $0.2 \le \lambda \le 0.4  \mu m$ $0.4 < \lambda \le 2.4  \mu m$	0.05% 0.01%	<b>Solar cycle variability</b> (S <sub>max</sub> /S <sub>min</sub> ) UV variability: 10% - 0.1% (Chromospheric) Vis-NIR variability: ≤ 0.05% (Photospheric)		
<b>Measurement precision</b> Spectral limits (0.2 - 2.4 μm)	0.01%	<b>Solar rotational variability</b> High SNR for Vis-NIR spectral repeatability		
<b>Measurement accuracy</b> Integrated spectral (0.2 - 2.4 μm)	0.25%	<b>Climate modeling input</b> Earth radiation budget: Solar attribution		
<b>Reporting cadence (per day)</b> Spectral limits (0.2 - 2.4 μm)	2	<b>Solar temporal variability</b> Sample diurnal spectral variabiliy (TSI correl.)		
Spectral resolution (nm) $\lambda \le 0.28 \ \mu m$ (Mg II) $0.28 \ \mu m < \lambda \le 0.40 \ \mu m$ (Ca II edge) $\lambda > 0.40 \ \mu m$ (photosphere)	1 5 45	Solar wavelength variability Strongest $\lambda$ -dependence in UV variability (Chromospheric origin) Broader $\lambda$ -dependence in Vis-NIR (Photospheric origin)		





## TSIS SIM Design Overview







## **TSIS SIM Components**







## Measurement Equation Overview





## **On-orbit calibration corrections**

#### Long-term corrections are key!



## Optical degradation (both wavelength and time dependent) is the largest contribution to the long-term measurement uncertainty

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SIM Electrical Substitution Radiometer (ESR)

50 Hz

The TSIS SIM ESR serves as a NIST traceable, space-qualified absolute calibration transfer detector



Active area: 8 mm x 1.5 mm (serpentine replacement R on backside)

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frequency (typ. 0.01 - 0.05 Hz)





## ESR Performance Meets Requirements for Solar Spectral Power







### SSI Variability and SIM Measurement Capabilities



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## **NIST SIRCUS Facility**

"Spectral Irradiance and Radiance Responsivity Calibrations with Uniform Sources"



Designed to reduce the uncertainty in spectral irradiance and radiance responsivity calibrations at the 0.1 % level and expand the spectral range where these uncertainty levels are achievable

The current uncertainty for SSI measurements is ~3 %. Current developments are directed at reducing this to a general goal of 0.25 % (k=1)





## **Characterization / Calibration Flow**

#### **Component-Level Calibrations:**

Slit Area Standard Watt Pulse-Width Modulation Linearity Shutter Waveform Servo Gain

#### $\lambda$ -dependent Calibrations:

Prism Geometry Prism Transmission Slit Diffraction ESR Efficiency Photodiode Sensitivity

#### Instrument-Level Calibrations:

Glint Field of View Wavelength Scale Absolute Instrument Function Area Scattered Light Science Field of View Servo Gain, Nonequivalence, Noise, etc.



## Calibration and characterization follows a measurement equation approach at the unit-level for full validation of end-to-end performance at the instrument-level





## TSIS SIM Calibration Error Budget

Instrument uncertainties determined at the component level --> characterization of error budget

	Measurement Correction	Origin	Value (ppm)	1σ (ppm)	
ent-Level Component-Level S/C	Distance to Sun, Earth & S/C	Analysis	33,537	0.1	
	Doppler Velocity	Analysis	43	1	
	Pointing	Analysis	0	100	Dominant uncertainties are -dependent
	Shutter Waveform	Component	100	10	
	Slit Area	Component	1,000,000	300	
	Diffraction	Component	5,000-62,000	500	
	Prism Transmittance	Component	230,000-450,000	1,000	98% of full budget
	ESR Efficiency (absorptance)	Component	1,000,000	1,000	
	Standard Volt + DAC	Component	1,000,000	50	
	Pulse Width Linearity	Component	0	50	
	Standard Ohm + Leads	Component	1,000,000	50	
	Instrument Function Area	Instrument	1,000,000	1,000	-
	Wavelength	Instrument	1,000,000	750	•
	Non-Equivalence, Z <sub>H</sub> /Z <sub>R</sub> -1	Instrument	2,000	100	
	Servo Gain	Instrument	2,000	100	Final systematic
mn	Dark Signal	Instrument	0	100	uncertainty quantification
Instru	Scattered Light	Instrument	0	200	requires full end-to-end
	Noise	Instrument	-	100	
	Combined Rel. Std. Uncertainty			2000	🛑 20% margin

Component-Level **DVD** Instrument-1

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## **TSIS SIM Calibration**

#### Full instrument-level calibration includes (all in vacuum):

- SIRCUS laser wavelength calibration
- Spectral instrument function measurements (Spectral PSF's)
  - ESR and Photodiodes (all channels)
- Absolute spectral irradiance calibration tied to NIST L1 Cryo
  - ESR (all channels)
- Channel to channel boresight alignment calibration
- Pointing and FOV mapping
  - For all calibrations above







## SIM Spectral Response Functions



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## SIM Spectral Response Functions



Direct determination: Fix prism, scan laser

$$S(\lambda_p,\lambda) = \int_{\Delta\lambda} E_{\lambda}(\lambda,\lambda') R_E(\lambda_p,\lambda') d\lambda'$$

Indirect determination: Fix laser, scan prism

$$S(\lambda,\lambda_o) = \kappa \int_{\Delta\lambda} E(\lambda',\lambda_o) \cdot r(\lambda',\lambda_o) d\lambda'$$
$$r(\lambda',\lambda_o) = r_f(\lambda') \cdot z(\lambda'-\lambda_o)$$



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## Preliminary Full Validation Results







## **Exposure Degradation over Mission Life**

On-orbit interchannel transmission comparisons track wavelength and exposure time dependent transmission loss

$$\begin{aligned} \mathcal{T}(\boldsymbol{\lambda}, t - t_0) &= \mathcal{T}(\boldsymbol{\lambda}, t_0) \, \mathrm{e}^{-\tau(\boldsymbol{\lambda}, t - t_0)} \\ \tau(\boldsymbol{\lambda}, t) &= \kappa(\boldsymbol{\lambda}) \cdot c(t) \end{aligned}$$

#### κ(λ) evaluated by periodic ESR measurements between separate channels

The degradation correction determined using the Channel A to Channel B ratio data measured twice per month

The Channel A to Channel C comparison (~1 per year) verifies the degradation correction

**Channel C** is to be used infrequently enough so that it can be considered "pristine" (less than 0.01%/year of degradation)





#### Fractional degradation vs. exposure time



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## Spectral degradation monitoring

ESR Channel A to Channel B comparison (over common wavelength intervals during the same solar viewing period) allows us to determine the prism degradation in the ESR measured irradiance.

For each measured wavelength interval, the ratio of the integrated A and B irradiances is proportional to the ratio of the prism degradation (within that interval) :

$$\frac{I_A}{I_B} \propto \frac{\left(\frac{Sun_t}{d(t_e^A)}\right)}{\left(\frac{Sun_t}{d(t_e^B)}\right)} = \frac{d(t_e^B)}{d(t_e^A)}$$



These measured ratios constrain a functional fit of the degradation (d) with respect to cumulative exposure time for each wavelength interval





## Determination of exposure time dependence

Determination of the degradation function (for each  $\bullet_i$ ) is based on repeated Channel A to Channel B calibration scans. For example, we assume an exponential decay as a function of exposure time and determine a decay constant alpha (5) for each wavelength interval



#### Schedule:

Every 19 days Channel A gets 100 hours of exposure, Channel B gets 5.3 hours. When Channel B reaches 100 hours exposure, we do a Channel C calibration.

When does B reach 100 hrs?

After 19 calibrations Channel B reaches 100 hour exposure:

 $19 \, day/cal \times 19 \, cal. = 362 \, days$ 

Remember. for each cal. we know

$$\frac{d(t_e^B)}{d(t_e^A)} = R_I^{AB}(t_{cal})$$

NOTE: Exposure time is 1-AU "corrected". 1 hour exposure (January)  $\neq$  1 hour exposure (July) !!

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## Summary

## Spectral Solar Irradiance (SSI) is critical to understanding solar variability and its impact on Earth climate

- TSIS SIM meets the JPSS measurement requirements for SSI variability, including:
  - High absolute irradiance accuracy (≤0.25% goal)
  - High measurement precision (<0.01% relative)
  - On-orbit capability to self-correct long-term drifts and sensitivity changes (<0.05% per year)</li>
    - Channel-to-channel calibrations
    - Direct measurements of optical components
    - Detector-to-detector calibrations
- TSIS SIM significant improvements over SORCE SIM include:
  - Long-term relative stability
    - Improved absolute ESR detector and duty-cycling 3 independent channels provides on-orbit calibration maintenance

#### - Measurement accuracy

• NIST calibration facilities (SIRCUS/POWR) provide SI-traceable pre-launch calibration





Back-up slides





## TSIS SIM Development Approach

#### TSIS SIM designed for long-term spectral irradiance measurements (climate research)

Incorporate lessons learned from SORCE SIM (& other LASP programs) into TSIS SIM to meet measurement requirements for long-term JPSS SSI record

#### Specific areas addressed in TSIS SIM development

✓ Reduce uncertainties in prism degradation correction to meet long-term stability requirement

- Ultra-clean optical environment to mitigate contamination
- Addition of 3<sup>rd</sup> channel to reduce calibration uncertainties

✓ Improve noise characteristics of ESR and photodiode detectors to meet measurement precision requirement

- ESR : Improved ESR thermal & electrical design
- Photodiodes : Larger dyn. range integrating ADC's (21-bits)

✓ Improve absolute accuracy pre-launch calibration

• NIST SI-traceable Unit and Instrument level pre-launch spectral calibrations (SIMRF-SIRCUS)









## Observed "Long-term" SSI Variability

Spectral Irradiance difference between Active in mid 2004 and Quiet in late 2007



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## Prism angle to wavelength mapping



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#### Three approaches that can be adopted

- Transfer the calibration from known "standard" instrument (1-3% unc.)
- Measure instrument response against an "irradiance standard" (~1% unc.)
- Characterize the instrument as an "absolute sensor" (<1% unc.)</li>
  - Characterize each term in the measurement eqn. model (may be a unit-level calibrations or calculations based on known uncertainties)
  - Establish uncertainty budget: tabulate list of all individual uncertainties and propagate – (random)
  - Validate end-to-end performance (systematic)



SORCE SIM and Atlas 3 Comparison (258-1350 nm)



# Full Spatial & Spectral Transmission Mapping

Prism measurement geometry is for ESR optical path Stabilized SIRCUS lasers cover 210 – 2400 nm range Refraction vs. wavelength (Suprasil 3001 fused silica) entrance slit  $n(\lambda,T)$ 64 optic axis  $\phi_{ESR}$ Measurements **y**<sub>ESR</sub> 63 TSIS SIM Model prism incidence angle (deg.) ESR 62 exit slit Transmission measured over 10 x 10 grid for both 61 s and p-polarizations dispersion 60 0.847 "p"-polarized 0.846 cross-dispersion 0.845 59 0.844 0.843 58 0.842 "s"-polarized 0.841 0.84 57 0.839 3 6 7 8 9 4 5 2 1000

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0.838



wavelength (nm)



## **Prism Transmission**



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